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			OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	··		
LJD	1	1-119945	04/1999	JAPAN			ABST.
LJD	7	7-152510	06/1995	JAPAN			ABST.
L7D	1	0-161820	06/1998	JAPAN			ABST.
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
			F	OREIGN PATENT DOCUMENTS			
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April 9, 2001				January 18, 2001		2621	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				RITSUKO OTAKE			
				APPLICANT			
FORM PTO 1449 (modified)				ATTY DOCKET NO. 35.C15046 APPLICATION NO. 09/761,759			'50

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet <u>1</u> of <u>1</u>